

<b>Notice of References Cited</b>	Application/Control No. 09/903,764	Applicant(s)/Patent Under Reexamination OKU ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0111730	06-2003	Takeda et al.	257/758
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08-236518	09-1996	Japan	Saito et al.	HO1L 21/316
	O					
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	R					
	S					
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**NON-PATENT DOCUMENTS**

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